FORM PTO-1449 (MODIFIED)	ATTY. DOCKET NO. ESD1.PAU.01	SERIAL NO. : 10/635,391
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT (USE SEVERAL SHEETS IF NECESSARY)	APPLICADO 100) 1 188 day at al.	
	FILING DATE, August 6, 2003	GROUP: 28H DES

Reference Designation

U.S. PATENTS

Examiner					Filing Date Subclass if		
Initial	Document Number	Date	Name	Class	appropriate		
MEN	6,153,913	11/28/2000	Hsu et al.		- Lappropriate		
7400	5,537,284	07/16/1996	Haas, Jr. et al.		 /		
6,157,530 6,268,286 6,034,388 6,331,726 5,689,133		12/05/2000	Pequignot et al.		 / 		
		07/31/2001	Gauthier, Jr. et al.		- 		
		03/07/2000	Brown et al.		- /		
			Voldman Voldman		/		
		12/18/2001					
		11/18/1997	Li et al.				
	6,292,343	09/18/2001	Pequignot et al.				
Ψ	6,262,873	07/17/2001	Pequignot et al.				
-							
				-			
	FOREIGN PATENT DOCUMENTS						
		·	DOCOMENTS		Filing Date		
					Subclass if		
	Document Number	Date	Country	Class	appropriate		
	OTHER ART (INCLU	L DING AUTHOR, TIT	LE, DATE, PERTINENT PA	GES, ETC.)			
May	Test Structures for Benchmarking the Electrostatic Discharge (ESD) Robustness of CMOS Technologies, Sematech, Inc., February 27, 1998						
	Characterization, Modeling,		rotection Circuits, Stephen G.	Beebe, Advanc	ed Micro		
	Devices, March 1998						
	Investigation of ESD Performance in Advanced CMOS Technology, A dissertation Submitted to the Department of Electrical Engineering and the Committee on Graduate Studies of Stanford University in Partia						
l							
	Fulfillment of the Requirements for the Degree of Doctor of Philosophy, Kwang-Hoon Oh, October 2002 Lighting Rods for Nanoelectronics, Steven H. Voldman, Scientific American, Vol. 287, No. 4, Pgs. 90-97, October 2002						
EXAMINE							
EXAMINE							
	mutot a Warner 9/22/04						